

percent, the all others rate established in the LTFV investigation.

These deposit requirements, when imposed, shall remain in effect until publication of the final results of the next administrative review.

This notice serves as a preliminary reminder to importers of their responsibility under 19 CFR 351.402(f) to file a certificate regarding the reimbursement of antidumping duties prior to liquidation of the relevant entries during this review period. Failure to comply with this requirement could result in the Secretary's presumption that reimbursement of antidumping duties occurred and the subsequent assessment of double antidumping duties.

This administrative review and notice are in accordance with sections 751(a)(1) and 777(i)(1) of the Act.

Dated: April 10, 2002

Faryar Shirzad,

Assistant Secretary for Import Administration.

[FR Doc. 02-9332 Filed 4-16-02; 8:45 am]

BILLING CODE 3510-DS-S

DEPARTMENT OF COMMERCE

International Trade Administration

The Pennsylvania State University; Notice of Decision on Application for Duty-Free Entry of Scientific Instrument

This decision is made pursuant to section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 a.m. and 5 p.m. in Suite 4100W, Franklin Court Building, U.S. Department of Commerce, 1099 14th Street, NW., Washington, DC.

Docket Number: 02-005.

Applicant: The Pennsylvania State University, University Park, PA 16802.

Instrument: Slow Scan CCD Camera, Model TemCam F-224.

Manufacturer: Tietz Video and Image Processing Systems GmbH, Germany.

Intended Use: See notice at 67 FR 10388, March 7, 2002.

Comments: None received.

Decision: Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as these instruments are intended to be used, was being manufactured in the United States at the time the instruments were ordered.

Reasons: The foreign instrument provides hardware and software compatibility and imaging comparability with previous studies by the applicant and with future studies to

be performed in collaboration with another institution which uses the foreign camera system. These advantages may not be readily attainable using an otherwise comparable domestic system. This capability is pertinent to the applicant's intended purposes and we know of no other instrument or apparatus of equivalent scientific value to the foreign instrument which is being manufactured in the United States.

Gerald A. Zerdy,

Program Manager, Statutory Import Programs Staff.

[FR Doc. 02-9334 Filed 4-16-02; 8:45 am]

BILLING CODE 3510-DS-P

DEPARTMENT OF COMMERCE

International Trade Administration

University of California, et al.; Notice of Consolidated Decision on Applications for Duty-Free Entry of Electron Microscopes

This is a decision consolidated pursuant to section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 a.m. and 5 p.m. in Suite 4100W, Franklin Court Building, U.S. Department of Commerce, 1099 14th Street, NW., Washington, DC.

Docket Number: 02-004.

Applicant: University of California, Lawrence Berkeley National Laboratory, Berkeley, CA 94720.

Instrument: Electron Microscope, Model JEM-2010.

Manufacturer: JEOL Ltd., Japan.

Intended Use: See notice at 67 FR 9652, March 4, 2002.

Order Date: October 25, 2001.

Docket Number: 02-006.

Applicant: St. Joseph's University, Philadelphia, PA 19131.

Instrument: Electron Microscope, Model JEM-1010.

Manufacturer: JEOL Ltd., Japan.

Intended Use: See notice at 67 FR 10389, March 7, 2002.

Order Date: October 2, 2001.

Comments: None received.

Decision: Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as these instruments are intended to be used, was being manufactured in the United States at the time the instruments were ordered. Reasons: Each foreign instrument is a conventional transmission electron microscope (CTEM) and is intended for research or scientific educational uses requiring a

CTEM. We know of no CTEM, or any other instrument suited to these purposes, which was being manufactured in the United States at the time of order of each instrument.

Gerald A. Zerdy,

Program Manager, Statutory Import Programs Staff.

[FR Doc. 02-9333 Filed 4-16-02; 8:45 am]

BILLING CODE 3510-DS-P

DEPARTMENT OF COMMERCE

International Trade Administration

Applications for Duty-Free Entry of Scientific Instruments

Pursuant to section 6(c) of the Educational, Scientific and Cultural Materials Importation Act of 1966 (Pub. L. 89-651; 80 Stat. 897; 15 CFR part 301), we invite comments on the question of whether instruments of equivalent scientific value, for the purposes for which the instruments shown below are intended to be used, are being manufactured in the United States.

Comments must comply with 15 CFR 301.5(a)(3) and (4) of the regulations and be filed within 20 days with the Statutory Import Programs Staff, U.S. Department of Commerce, Washington, DC 20230. Applications may be examined between 8:30 A.M. and 5:00 P.M. in Suite 4100W, U.S. Department of Commerce, Franklin Court Building, 1099 14th Street, NW, Washington, DC.

Docket Number: 02-009. *Applicant:* The University of Akron, 302 E. Buchtel Avenue, Akron, OH 44325. *Instrument:* Shielded Room (Low Field Cage) MMLFC. *Manufacturer:* Magnetic Measurements Ltd., United Kingdom. *Intended Use:* The instrument is intended to be used to study remanent magnetic properties of sediments using samples from a variety of geologic settings such as lakes, river terraces and loess-soil profiles. Also, the instrument will be used in the following courses: (1) Environmental Magnetism (3370:444/544), (2) Research Problems in Geology (3370:499) and (3) Master's thesis (3370:699). Application accepted by Commissioner of Customs: March 21, 2002.

Docket Number: 02-011. *Applicant:* University of Wisconsin—Milwaukee, Department of Physics, 1900 E. Kenwood Blvd., Milwaukee, WI 53211. *Instrument:* IR Image Furnace, Model SCI-MDH-11020. *Manufacturer:* NEC Machinery Corporation, Japan. *Intended Use:* The instrument is intended to be used for the synthesis of single crystals of electronic-oxide materials using a